

Latest evolutions of the CIVA simulation platform & applications

NDT IN CANADA
2011 CONFERENCE



EXTEN·D·E
CIVA

cea list

energie atomique • énergies alternatives

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26/10/2011

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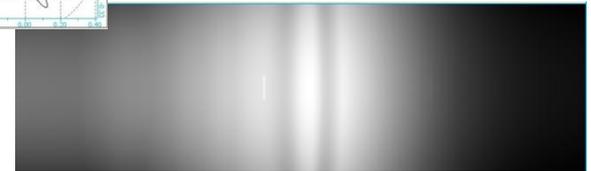
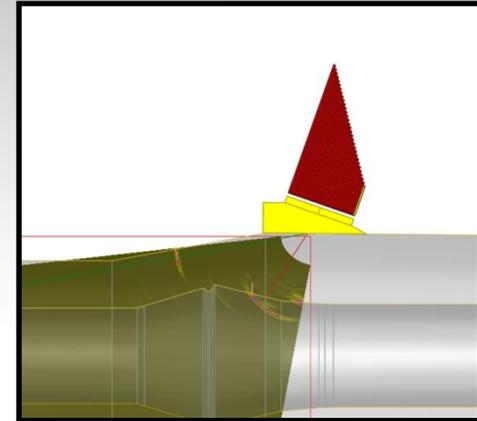
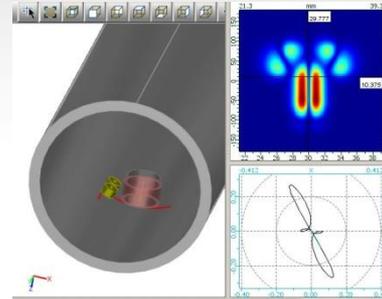
- | CIVA, version 10.0
- | Benefits of simulation:
 - UT: Applications to performance demonstration
 - ET: Introduction of innovative process
 - RT: Design of inspection method
 - POD: Towards more efficient POD campaign

CIVA

| Dedicated NDE modeling tool

| Multi-techniques :

- UT : Ultrasounds
- ET : Eddy Current
- RT : Radiography



| Developed by CEA (French Atomic Energy commission: Research center)

- NDT department: 100 people
- Development & validation CIVA: 30 people

| Semi-analytical models

| Distributed by EXTENDE from 2010

EXTENDE activities

| CIVA Distribution:

- Extende Inc. (based in NY, USA) for US and CANADA:
- Our representative: Erica SCHUMACHER



| Technical support

| Training courses

| Consulting:



- Software used: CIVA, Flux

| Research & Development: Collaborative projects

- | CIVA V10, **user oriented**: Re-organized environment
 - More intuitive, more interactive, results “integrated” in one analysis window, etc.

- | CIVA V10, numerous **new capabilities**:
 - UT: Defect response calculations available in 3D CAD work piece geometries, branched defects, specific models for cast steels, multi-skips accounted for, Total Focusing Method, etc.

 - ET: Multiple defects, New sensors (GMR, Arrays,...)

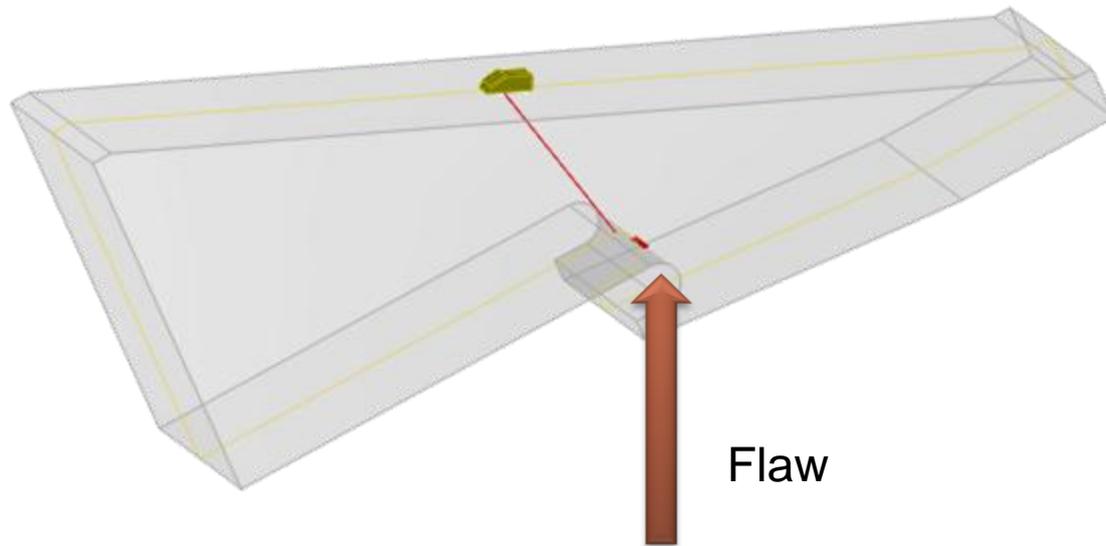
 - RT: Dramatic improvement of the ergonomics and the computation performance, accounts for detector granularity

 - Computation of POD (Probability Of Detection) curves

 - Etc.

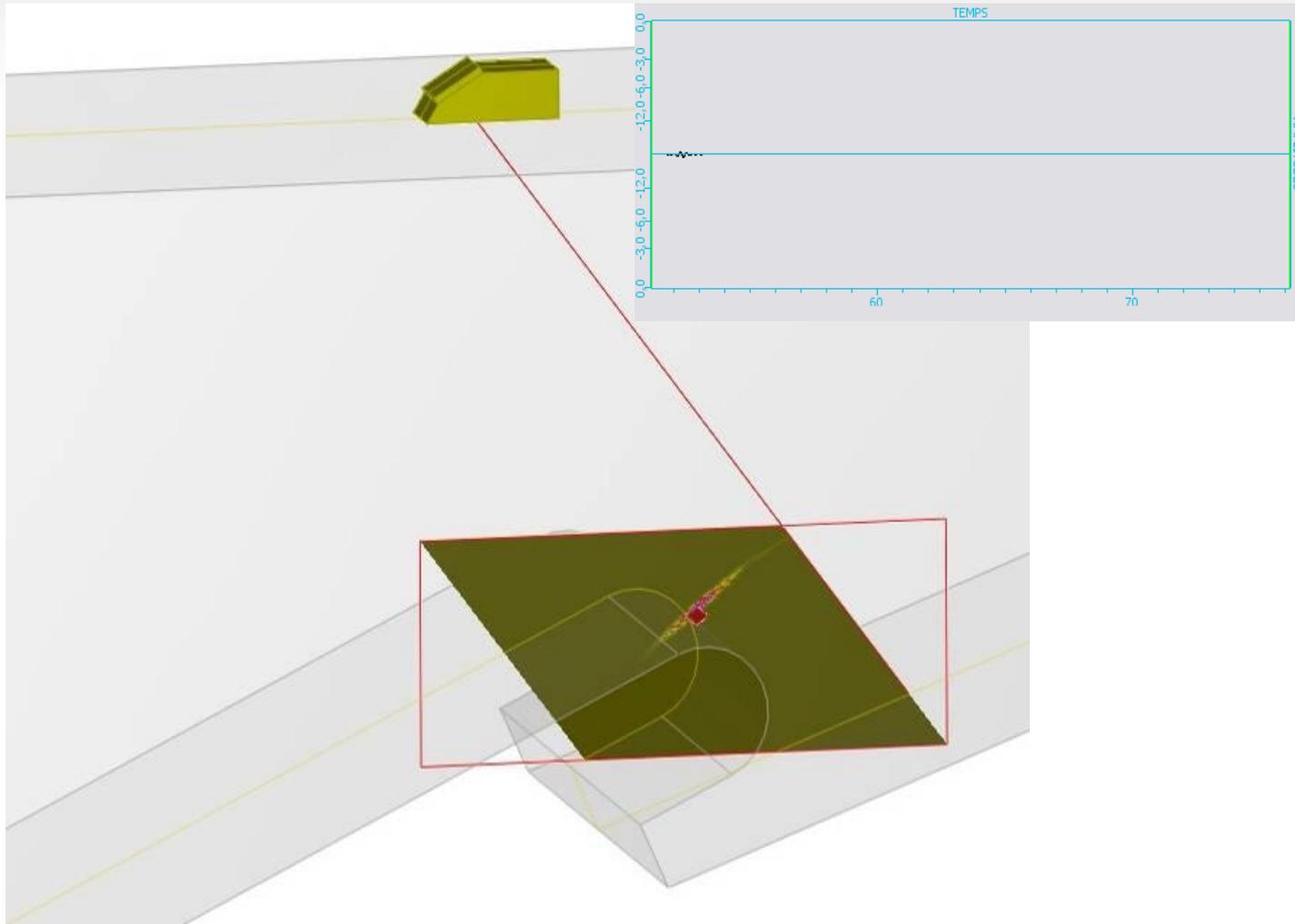
UT : Design and qualification of inspection methods

- | Inspection of a steam generator thermal sleeve
- | Contact probe SV 45



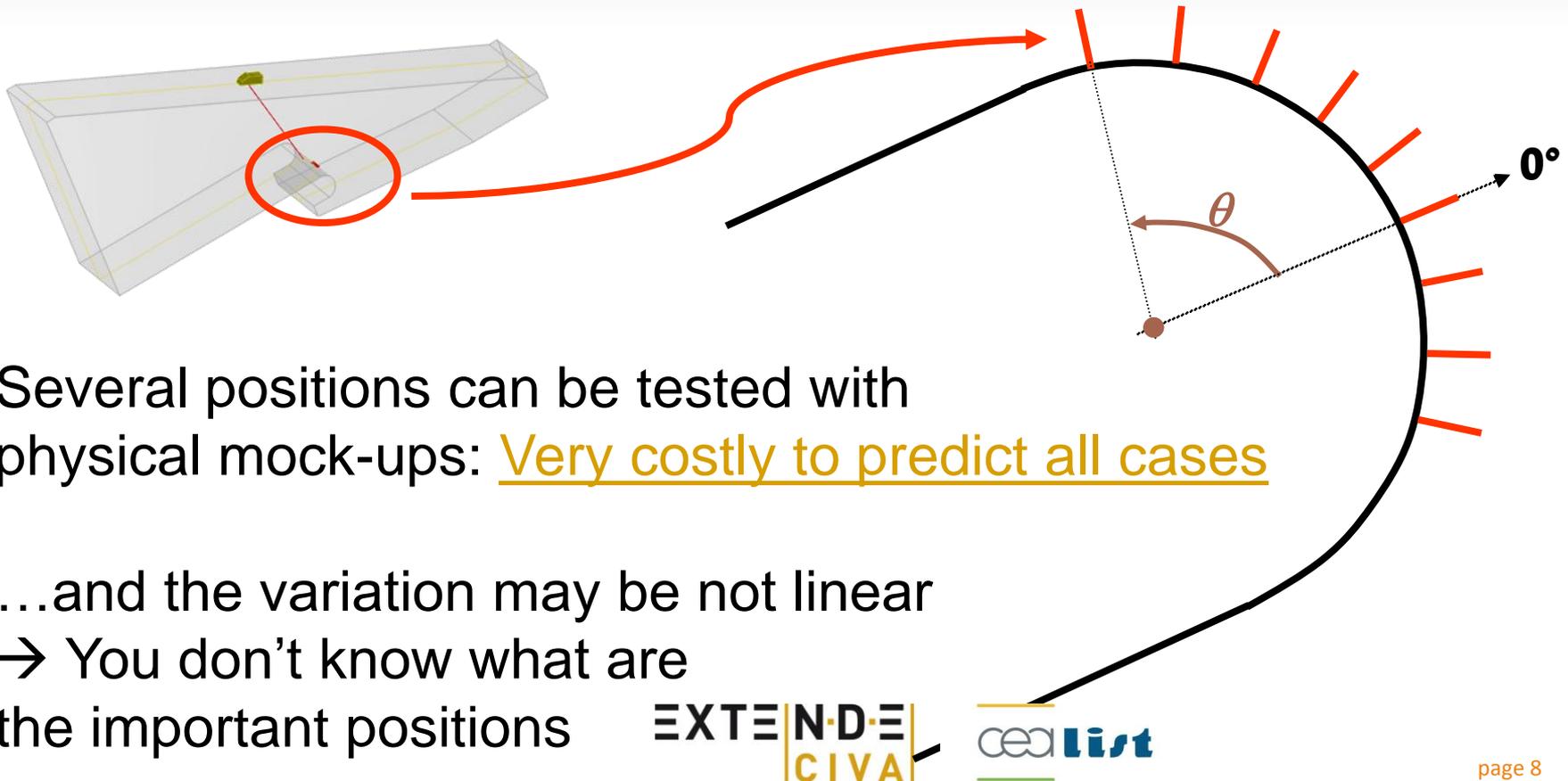
UT : Design and qualification of inspection methods

- | Simulation allows to predict the probe performance:



UT : Design and qualification of inspection methods

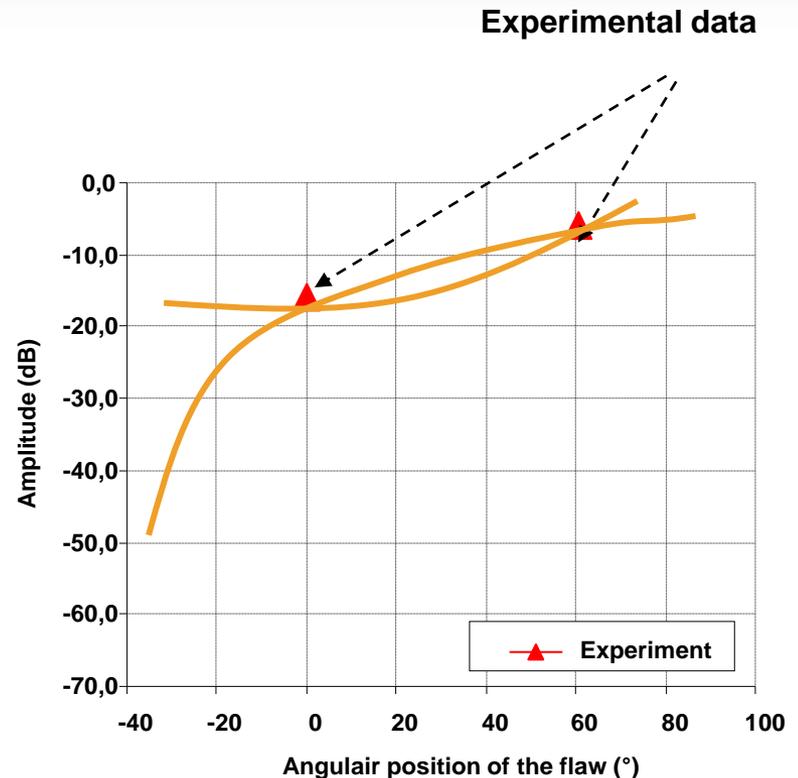
- | What will be the influence of the flaw position on the signal? Limits of performance ?



UT : Design and qualification of inspection methods

Proposed methodology:

- Acquisition for 2 (or 3) flaws positions with mock-ups
- Measurements gives some elements but does not give the full variation curve



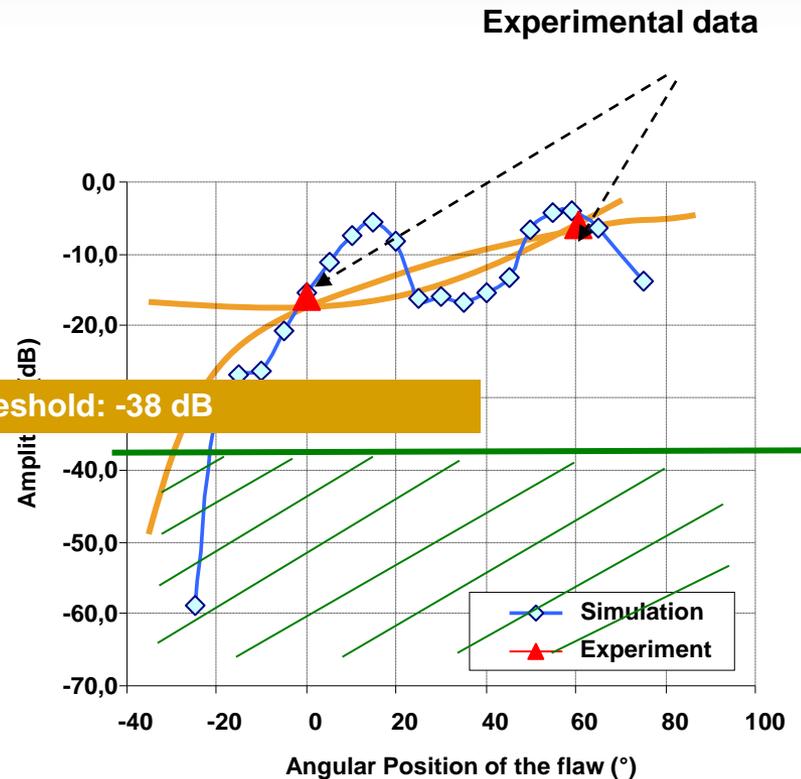
UT : Design and qualification of inspection methods

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Parametric study
with simulation

- Allows to complete the results vs procedure criteria
- Crossed validation :
Measurements / Simulations
- Cost efficient



ET : Introduction of innovative process

Example: ET array sensor

- Example of a sensor development made at CEA*:
 - 2 sets of 32 microcoils
 - Printed on a flexible kapton film
 - Silicone Roll to ensure good contact with the workpiece during scanning



- Advantages :
 - **Good resolution** for the detection of small cracks
 - **Flexibility** provided by the multi-elements monitoring
 - **Limitation** of disturbing effects due to **lift-off variation**

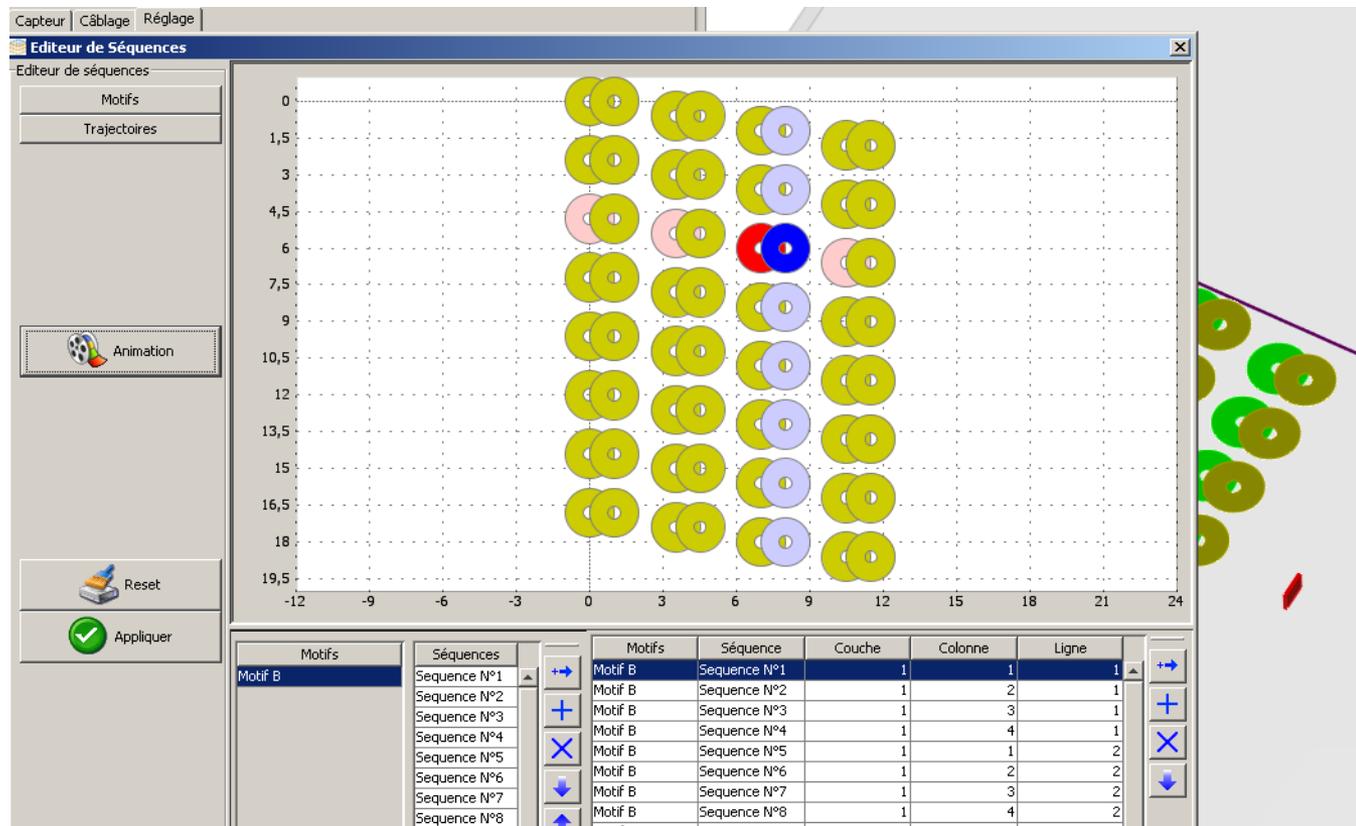
Simulation: Helps the design

*See : "Flexible and array eddy current probes for fast inspection of complex parts", B.Marchand, J. M. Decitre, and O. Casula, QNDE 2010

ET : Introduction of innovative process

CIVA10: Built-in tools for ET arrays:

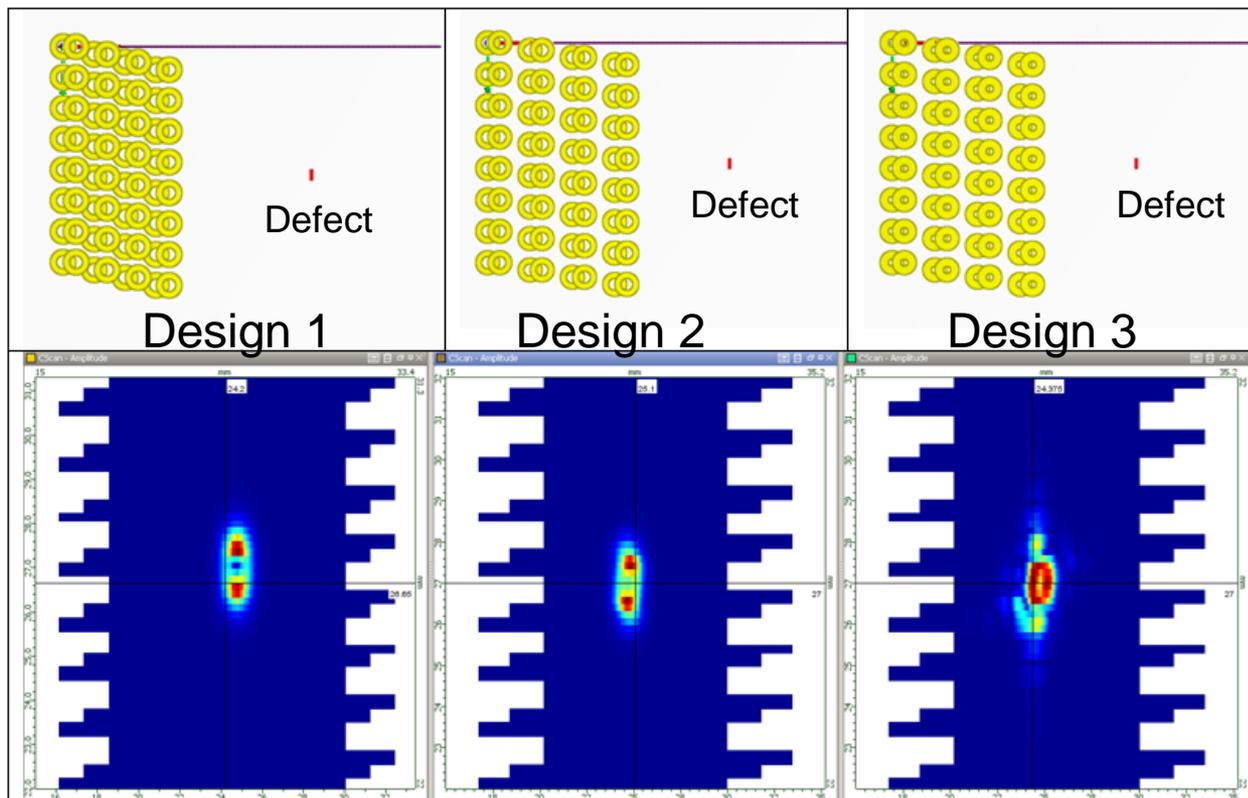
- Geometrical description of winding layers
- Definition of wiring
- Definition of channels: “Patterns “and electronic “trajectories”



Motifs	Séquences	Motifs	Séquence	Couche	Colonne	Ligne
Motif B	Sequence N°1	Motif B	Sequence N°1	1	1	1
	Sequence N°2	Motif B	Sequence N°2	1	2	1
	Sequence N°3	Motif B	Sequence N°3	1	3	1
	Sequence N°4	Motif B	Sequence N°4	1	4	1
	Sequence N°5	Motif B	Sequence N°5	1	1	2
	Sequence N°6	Motif B	Sequence N°6	1	2	2
	Sequence N°7	Motif B	Sequence N°7	1	3	2
	Sequence N°8	Motif B	Sequence N°8	1	4	2

ET : Introduction of innovative process

- Comparison of 3 designs (defect $0.4 \times 0.2 \times 0.1 \text{ mm}^3$)
 - 1 mechanical scanning axis / Acquisition 1Mhz
 - Design 2 vs Design 1: Variation of inter-coils distances
 - Design 3 vs Design 2: Variation of coils sizes



ET : Introduction of innovative process

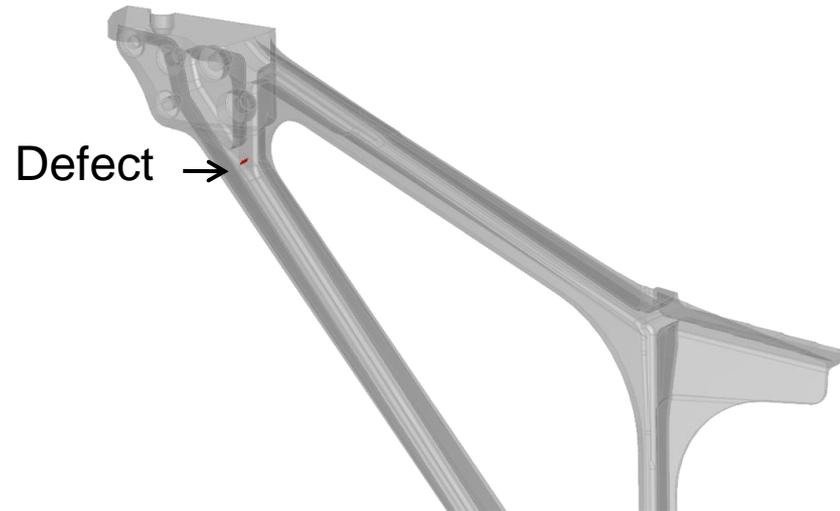
- | Benefits of simulation:
 - **Virtual prototyping** allows to test numerous solutions before creating a physical prototype :
 - Time & cost saving: **Less prototypes**
 - Enhanced performances
 - **Evaluate before investing**: Virtually compare an existing conventional technique with an innovative one
 - **New Technologies**: It means by definition few feedback. Simulation allows to **better understand** and handle a new technique at low cost

RT : Preparing an inspection

- | Stiffener inspection with an X-ray source

- | Problematic: Select the best settings **before inspection**:
 - Limit the number of shots
 - Limit the operation time

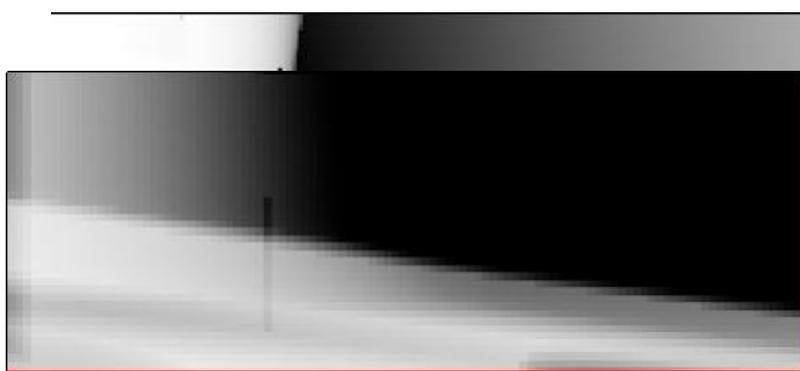
- | Parameters:
 - Which source to select among 3 available?
 - Which film?
 - Ideal positioning & source/film distance ?
 - Which exposure time ?



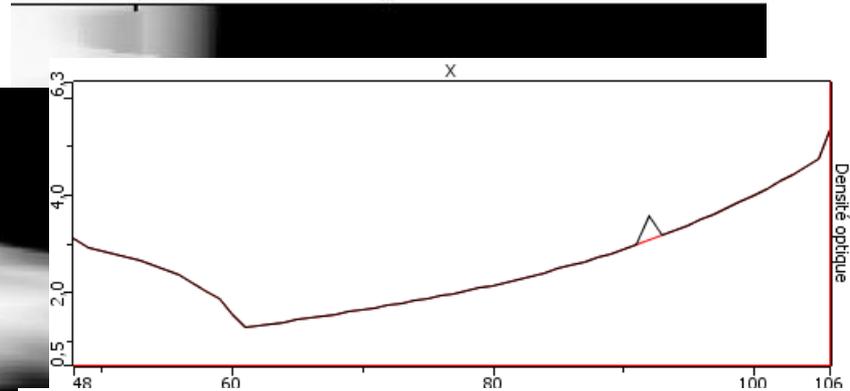
RT : Preparing an inspection

Performance comparison with 3 different sources:

- Source at 140 kV/5mA
- Source at 200 kV/5mA
- Source at 300 kV/5mA



300kV / 5mA source. 2
140kV / 5mA source. 2
around the defect



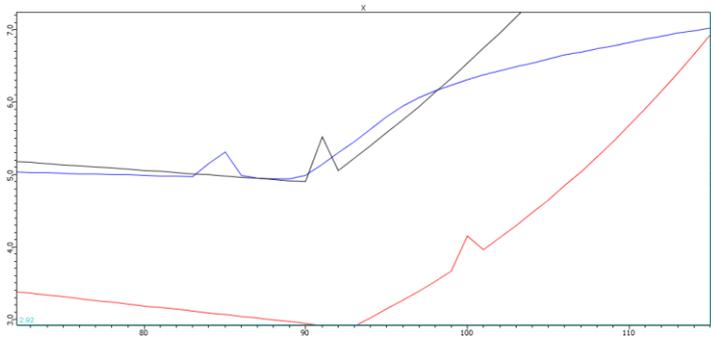
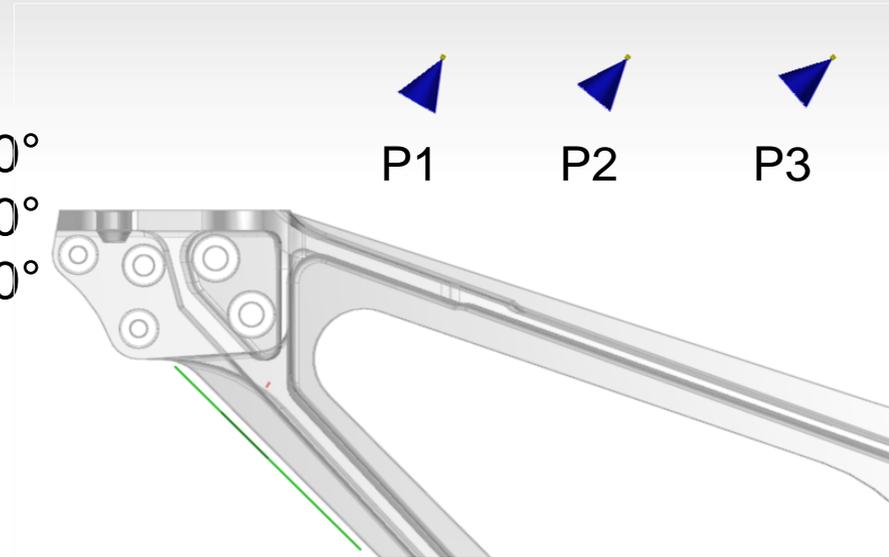
Good def
300kV/5mA source. 2
Curve of the optical density extracted at a cross-section nearby the flaw

RT : Preparing an inspection

| With the selected source : Optimization of the position of the source:

| Comparison with 3 positions

- P1: X = 300 mm / orientation -30°
- P2: X = 500 mm / orientation -40°
- P3: X = 700 mm / orientation -50°



- P1: Orientation - 30°
- P2: Orientation - 40°
- P3: Orientation - 50°

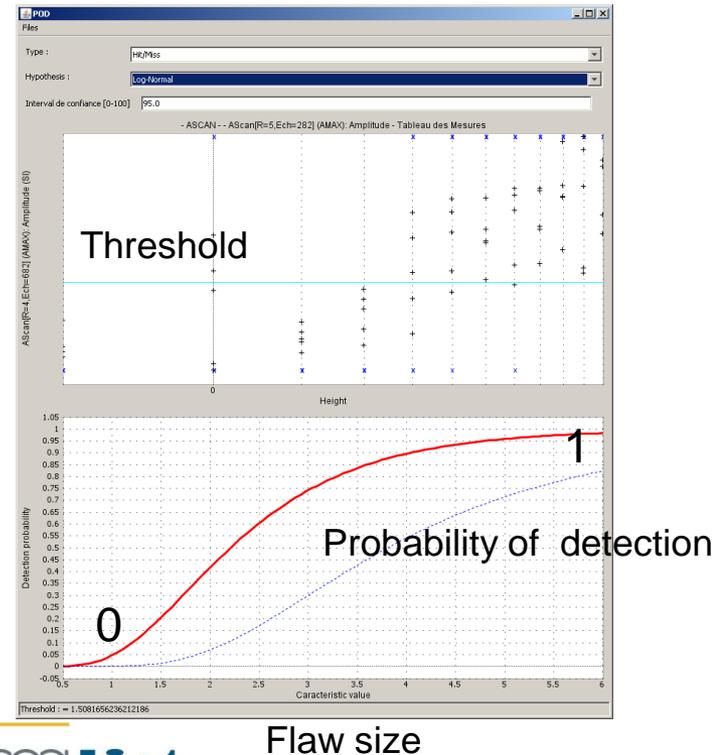
Position/orientation	Δ DO (with & without flaw)
300mm/-30°	0,29
500mm/-40°	0,54
700mm/-50°	0,31

POD in a few words

- | A POD curve links the defect detectability to its **size**

- | For **1 defect size**, the POD gives the **probability** of this flaw to be **detected** for a given **threshold**

- | This probability depends on **influential and uncertain parameters**



POD in a few words

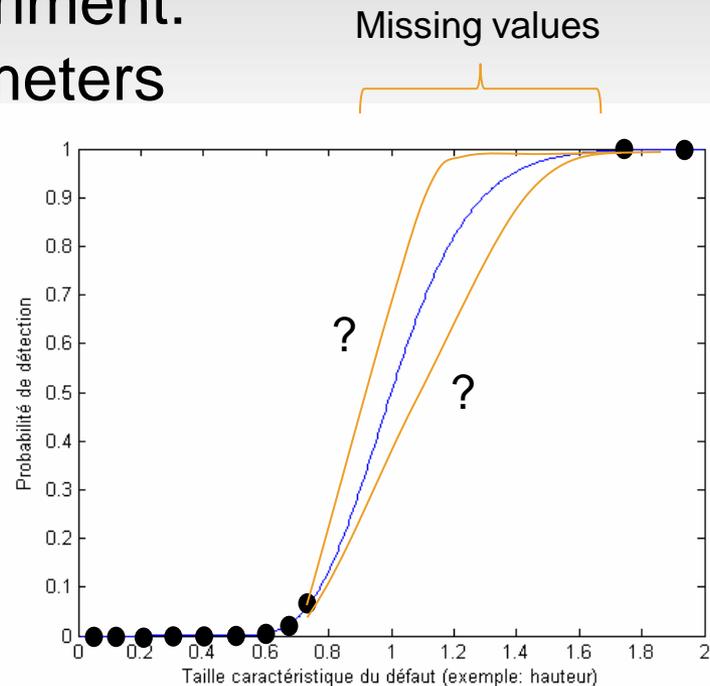
- | Methods that have to be applied and rules that have to be respected to have a reliable POD are **heavy and cost consuming**.
 - MIL-HDBK-1823 (aeronautics)
 - DNV-OS-F101 Appendix E (oil & gaz)
 - ...

- | Building a POD implies **many** mock-up, most finally **destroyed** to have references, many acquisitions, analysis...

Benefits of simulation POD

| Optimize design of experiment:
Find the influential parameters

| If measurements are not in the **interesting area of uncertainty**, the result obtained with mock-ups does not give satisfaction and **cost is increasing**.

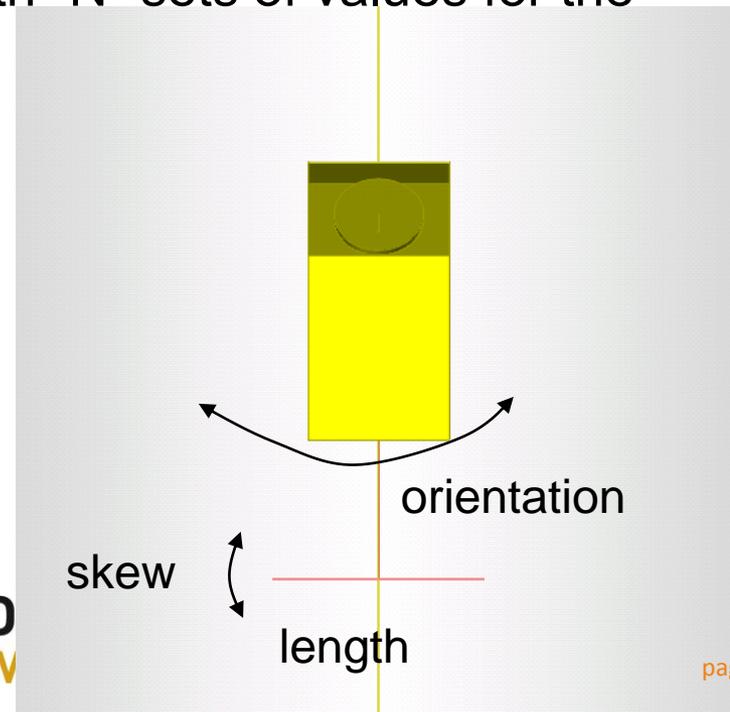
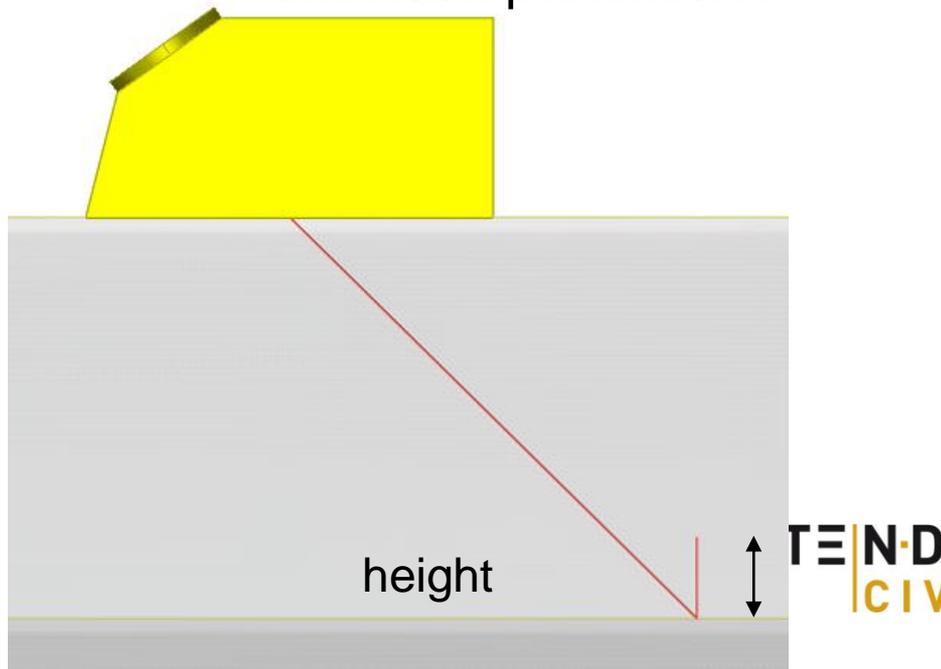


| **Adapted domains of uncertainties** may be found thanks to simulation **before** making mock-up.

POD in CIVA software

I User defines:

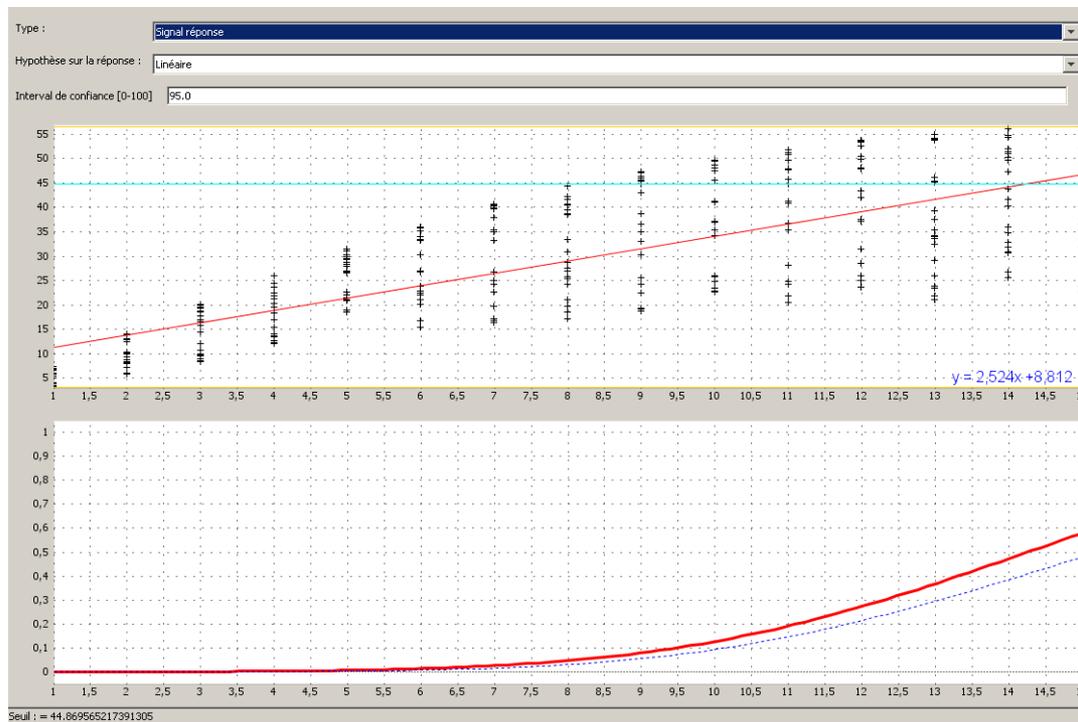
1. Nominal configuration”
2. Characteristic quantity → e.g. Defect height
3. Uncertain parameters and their statistical distribution
→ e.g. Defect skew, probe orientation
4. Run the “N” computation with “N” sets of values for the uncertain parameters



POD : Application

CIVA gives:

- The whole set of results for each case (Ascan, Bscan, etc.)
- The POD curve and associated parameters
 - Inspection procedure **thresholds** (detection, noise level, saturation)
 - Type of data: Signal Response/Hit-Miss
 - Confidence bound



Conclusion



- | CIVA V10.0 : A reorganized environment & enhanced simulation capabilities
- | Simulation can now also help to support a POD campaign: More reliable curves at low cost
- | Numerous applications available for 3 techniques: UT,ET,RT
 - Design and qualification of inspection methods
 - Innovation
 - Preparation of inspection
 - Expertise
 - Training